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Characteristic	Symbol	Value	Unit	
Drain-Source Voltage	V <sub>DSS</sub>	-60	V	
Gate-Source Voltage	V <sub>GSS</sub>	±20	V	
Drain Current (Note 7) V <sub>GS</sub> = -10V t < 10s	$T_A = +25$ °C $T_A = +70$ °C	I <sub>D</sub>	-4.5 -3.6	А
Maximum Body Diode Forward Current (Note 7)	I <sub>S</sub>	-2.1	A	
Pulsed Drain Current (10μs Pulse, Duty Cycle = 1%)	I <sub>DM</sub>	-19	A	
Avalanche Current (Note 8) L = 0.1mH	I <sub>AS</sub>	-17.6	A	
Avalanche Energy (Note 8) L = 0.1mH	E <sub>AS</sub>	15.4	mJ	

#### Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 6)		P <sub>D</sub>	1.5	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	C	80	°C/W
Thermal Resistance, Junction to Ambient (Note 6)	t<10s	$R_{\theta JA}$	48	°C/W
Total Power Dissipation (Note 7)		P <sub>D</sub>	2.0	W
Thermal Resistance, Junction to Ambient (Note 7)	Steady State	D	61	°C/W
Thermal Resistance, Junction to Ambient (Note 1)	t<10s	$R_{\theta JA}$	37	°C/W
Thermal Resistance, Junction to Case		$R_{ heta JC}$	6.4	°C/W
Operating and Storage Temperature Range		$T_{J,}T_{STG}$	-55 to +150	°C

## **Electrical Characteristics** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 9)	OFF CHARACTERISTICS (Note 9)					
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-60	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	-1	μA	V <sub>DS</sub> = -48V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	_	_	100	nA	$V_{GS} = \pm 16V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 9)	ON CHARACTERISTICS (Note 9)					
Gate Threshold Voltage	$V_{GS(TH)}$	-1	_	-3	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
Static Drain-Source On-Resistance		_	86	110	mΩ	$V_{GS} = -10V, I_D = -4.5A$
	R <sub>DS(ON)</sub>	_	98	130		$V_{GS} = -4.5V, I_{D} = -3.5A$
Diode Forward Voltage	V <sub>SD</sub>	_	-0.7	-1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -1A
DYNAMIC CHARACTERISTICS (Note 10)						
Input Capacitance	Ciss	_	1030	_	pF	V <sub>DS</sub> = -30V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	Coss	_	49.1	_		
Reverse Transfer Capacitance	C <sub>rss</sub>	_	38.7	_		
Gate Resistance	$R_G$	_	13.6	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$
Total Gate Charge (V <sub>GS</sub> = -4.5V)	Qg	_	9.5	_		V <sub>DS</sub> = -30V, I <sub>D</sub> = -5A
Total Gate Charge (V <sub>GS</sub> = -10V)	Qg	_	19.4	_		
Gate-Source Charge	$Q_{gs}$	_	2.3	_	nC	
Gate-Drain Charge	Q <sub>gd</sub>	_	3.6	_		
Turn-On Delay Time	t <sub>D(ON)</sub>	_	3.7	_	ns	$V_{GS}$ = -10V, $V_{DS}$ = -30V, $R_{GEN}$ = $6\Omega$ , $I_D$ = -5A
Turn-On Rise Time	t <sub>R</sub>	_	6.3	_		
Turn-Off Delay Time	t <sub>D(OFF)</sub>	_	58.7	_	115	
Turn-Off Fall Time	t <sub>F</sub>	_	26.1	_		
Body Diode Reverse Recovery Time	t <sub>RR</sub>		14.85		ns	$I_S = -5A$ , $dI/dt = 100A/\mu s$
Body Diode Reverse Recovery Charge	Q <sub>RR</sub>		8.8		nC	$I_S = -5A$ , $dI/dt = 100A/\mu s$

6. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.

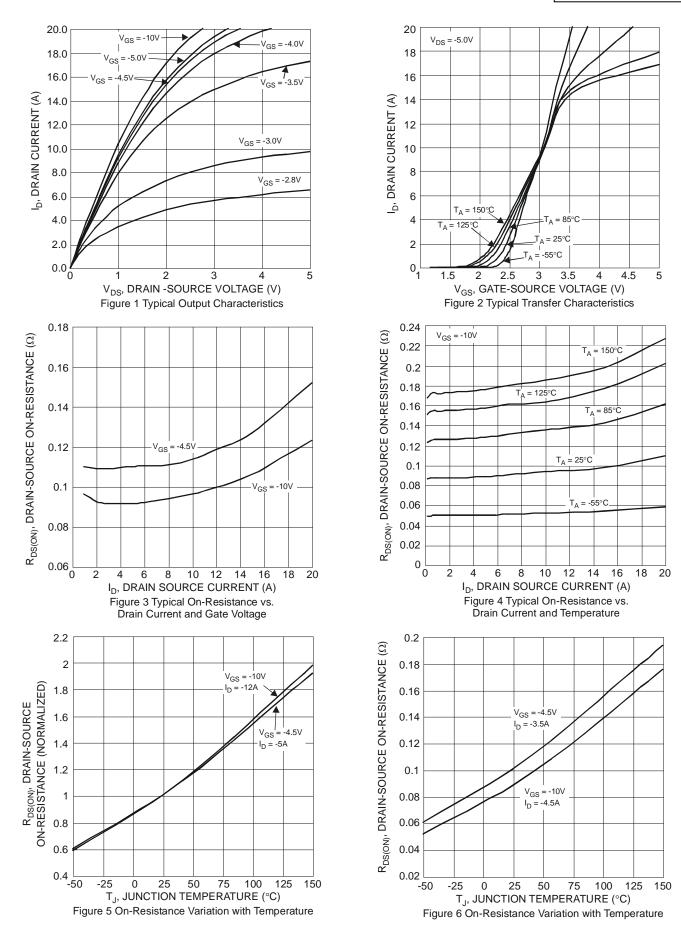
7. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

8. UIS in production with L = 0.1mH, starting T<sub>A</sub> = +25°C.

9. Short duration pulse test used to minimize self-heating effect.

10. Guaranteed by design. Not subject to product testing. Notes:







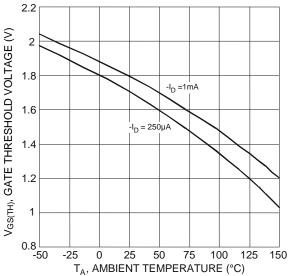
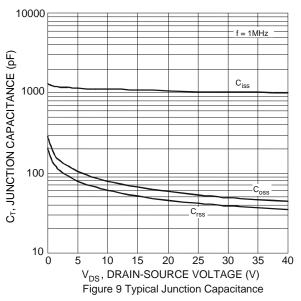
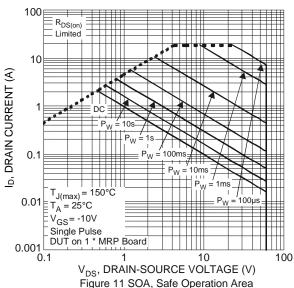
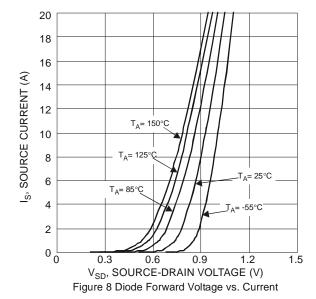
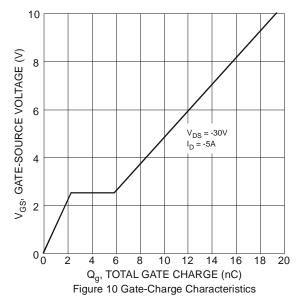


Figure 7 Gate Threshold Variation vs. Ambient Temperature

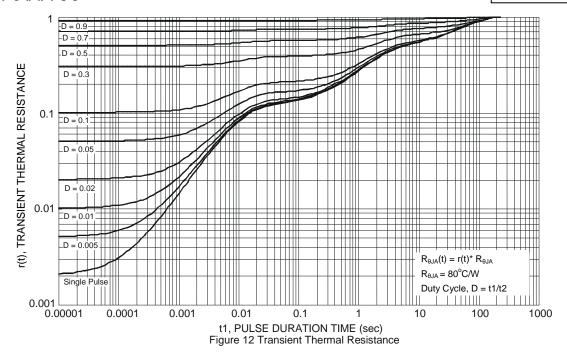






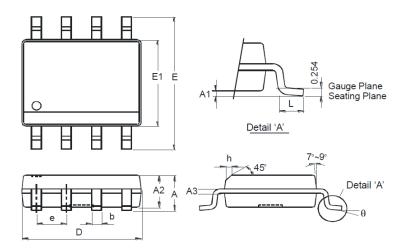






### **Package Outline Dimensions**

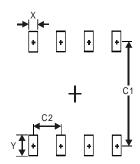
Please see http://www.diodes.com/package-outlines.html for the latest version.



SO-8				
Dim	Min	Max		
Α	-	1.75		
A1	0.10	0.20		
A2	1.30	1.50		
A3	0.15	0.25		
b	0.3	0.5		
D	4.85	4.95		
Е	5.90	6.10		
E1	3.85	3.95		
е	1.27 Typ			
h	-	0.35		
L	0.62	0.82		
θ	0°	8°		
All Dimensions in mm				

### **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.



Dimensions	Value (in mm)
Х	0.60
Υ	1.55
C1	5.4
C2	1.27



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